

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSV)

# 2SK3407

## Switching Regulator Applications

- Low drain-source ON resistance:  $R_{DS(ON)} = 0.48 \, \Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 7.5 \, S$  (typ.)
- Low leakage current:  $I_{DSS} = 100 \, \mu A$  (max) ( $V_{DS} = 450 \, V$ )
- Enhancement-mode:  $V_{th} = 2.4 \sim 3.4 \, V$  ( $V_{DS} = 10 \, V$ ,  $I_D = 1 \, mA$ )

### Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit
Drain-source voltage		$V_{DSS}$	450	V
Drain-gate voltage ( $R_{GS} = 20\text{ k}\Omega$ )		$V_{DGR}$	450	V
Gate-source voltage		$V_{GSS}$	$\pm 30$	V
Drain current	DC (Note 1)	$I_D$	10	A
	Pulse (Note 1)	$I_{DP}$	40	
Drain power dissipation ( $T_c = 25^\circ\text{C}$ )		$P_D$	40	W
Single pulse avalanche energy (Note 2)		$E_{AS}$	222	mJ
Avalanche current		$I_{AR}$	10	A
Repetitive avalanche energy (Note 3)		$E_{AR}$	4	mJ
Channel temperature		$T_{ch}$	150	$^\circ\text{C}$
Storage temperature range		$T_{stg}$	$-55\sim 150$	$^\circ\text{C}$

**Note:** Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

## Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	$R_{th(ch-c)}$	3.125	°C/W
Thermal resistance, channel to ambient	$R_{th(ch-a)}$	62.5	°C/W

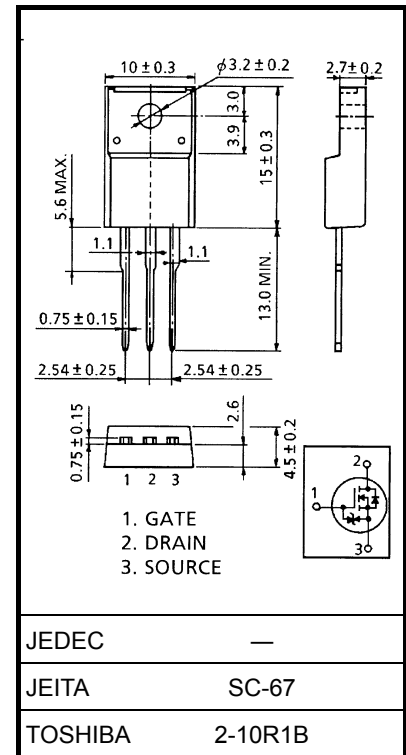
Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2:  $V_{DD} = 90\text{ V}$ ,  $T_{ch} = 25^\circ\text{C}$  (initial),  $L = 3.7\text{ mH}$ ,  $R_G = 25\ \Omega$ ,  $I_{AR} = 10\text{ A}$

Note 3: Repetitive rating; pulse width limited by maximum channel temperature.

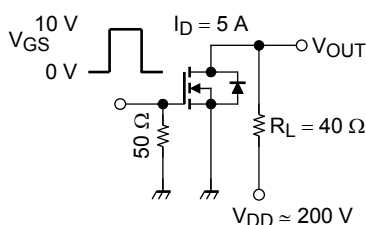
This transistor is an electrostatic sensitive device. Please handle with caution.

Unit: mm



Weight: 1.9 g (typ.)

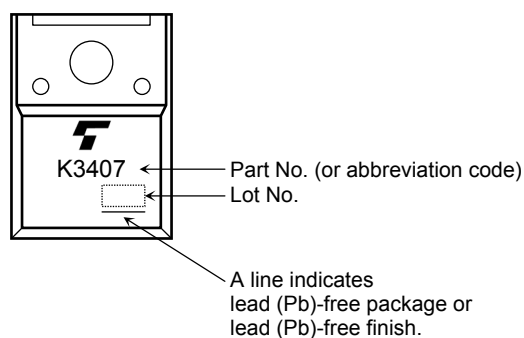
## Electrical Characteristics (Ta = 25°C)

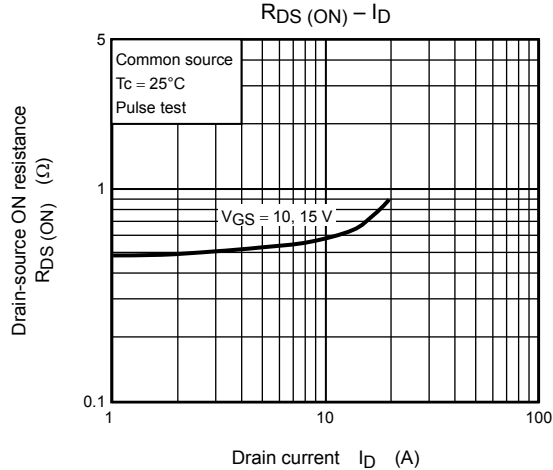
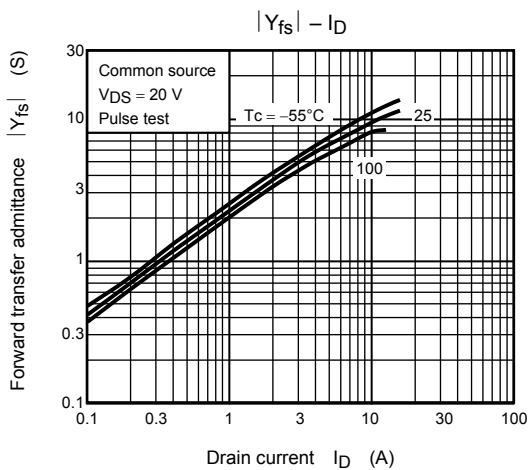
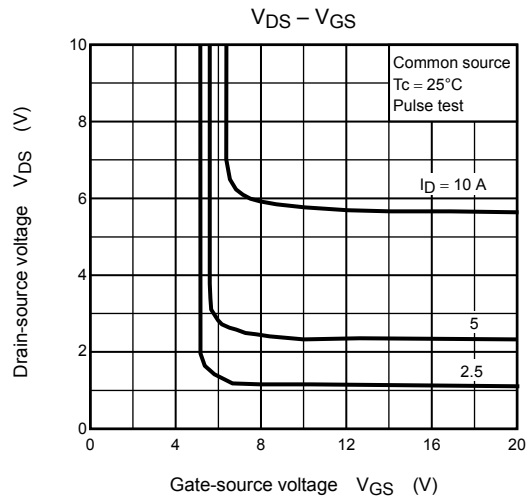
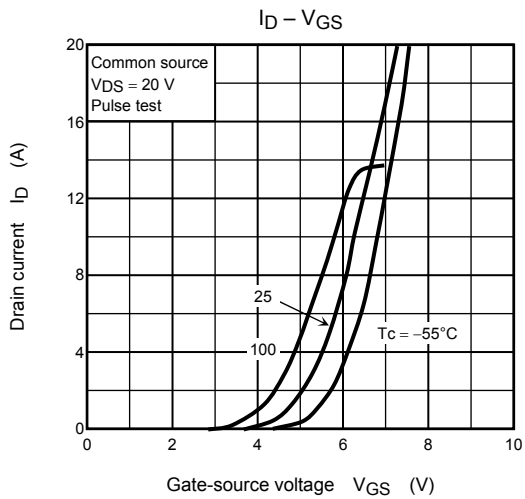
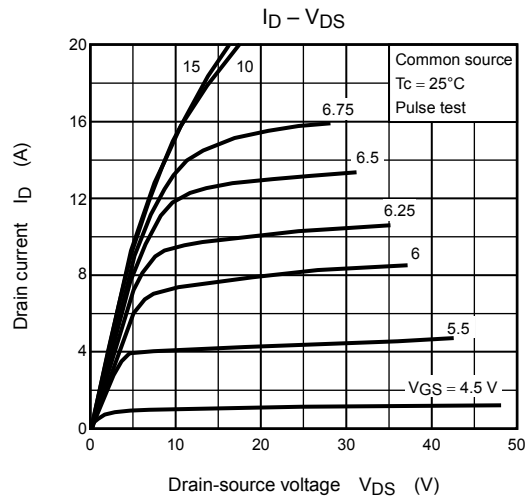
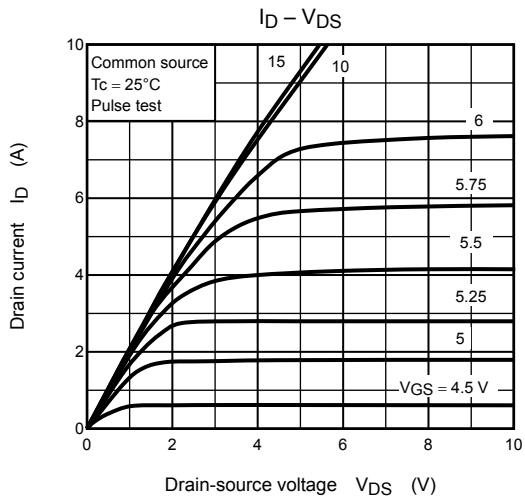
Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		$I_{GSS}$	$V_{GS} = \pm 25 \text{ V}$ , $V_{DS} = 0 \text{ V}$	—	—	$\pm 10$	$\mu\text{A}$
Gate-source breakdown voltage		$V_{(BR)GSS}$	$I_G = \pm 10 \mu\text{A}$ , $V_{DS} = 0 \text{ V}$	$\pm 30$	—	—	V
Drain cut-off current		$I_{DSS}$	$V_{DS} = 450 \text{ V}$ , $V_{GS} = 0 \text{ V}$	—	—	100	$\mu\text{A}$
Drain-source breakdown voltage		$V_{(BR)DSS}$	$I_D = 10 \text{ mA}$ , $V_{GS} = 0 \text{ V}$	450	—	—	V
Gate threshold voltage		$V_{th}$	$V_{DS} = 10 \text{ V}$ , $I_D = 1 \text{ mA}$	2.4	—	3.4	V
Drain-source ON resistance		$R_{DS(ON)}$	$V_{GS} = 10 \text{ V}$ , $I_D = 5 \text{ A}$	—	0.48	0.65	$\Omega$
Forward transfer admittance		$ Y_{fs} $	$V_{DS} = 10 \text{ V}$ , $I_D = 5 \text{ A}$	3.5	7.5	—	S
Input capacitance		$C_{iss}$	$V_{DS} = 10 \text{ V}$ , $V_{GS} = 0 \text{ V}$ , $f = 1 \text{ MHz}$	—	1400	—	pF
Reverse transfer capacitance		$C_{rss}$		—	240	—	
Output capacitance		$C_{oss}$		—	590	—	
Switching time	Rise time	$t_r$	 <p><math>I_D = 5 \text{ A}</math> <math>V_{GS} = 10 \text{ V}</math> <math>V_{DS} = 0 \text{ V}</math> <math>50 \Omega</math> <math>R_L = 40 \Omega</math> <math>V_{DD} \approx 200 \text{ V}</math> Duty <math>\leq 1\%</math>, <math>t_w = 10 \mu\text{s}</math></p>	—	35	—	ns
	Turn-on time	$t_{on}$		—	50	—	
	Fall time	$t_f$		—	80	—	
	Turn-off time	$t_{off}$		—	260	—	
Total gate charge (gate-source plus gate-drain)		$Q_g$	$V_{DD} \approx 360 \text{ V}$ , $V_{GS} = 10 \text{ V}$ , $I_D = 10 \text{ A}$	—	35	—	nC
Gate-source charge		$Q_{gs}$		—	19	—	
Gate-drain "miller" charge		$Q_{gd}$		—	16	—	

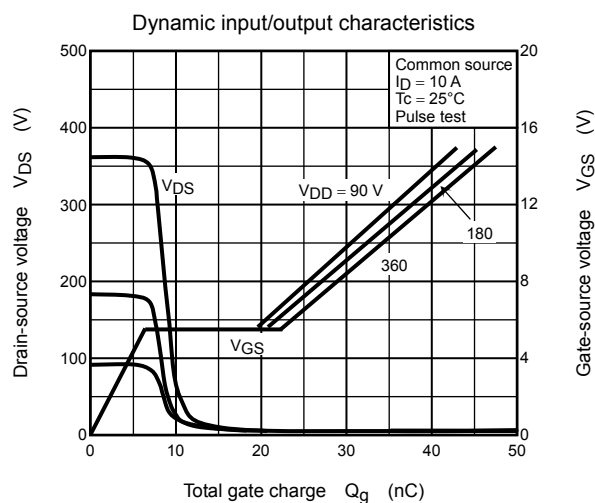
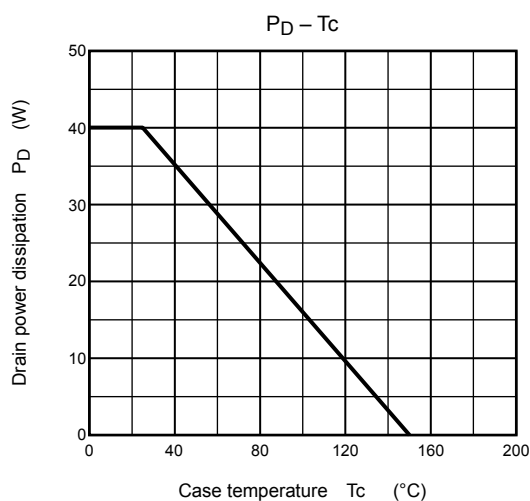
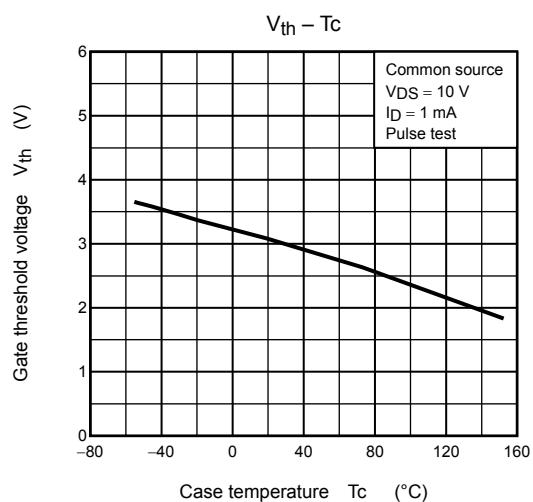
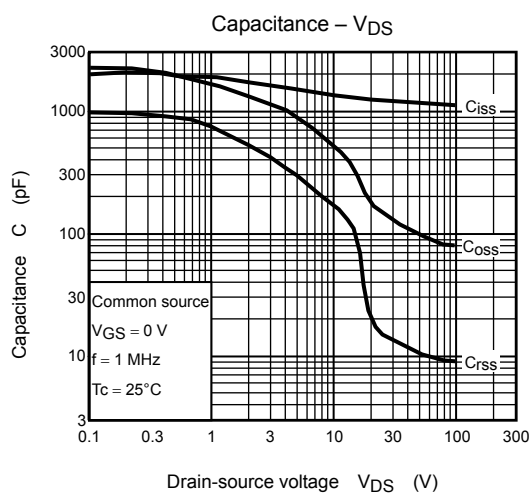
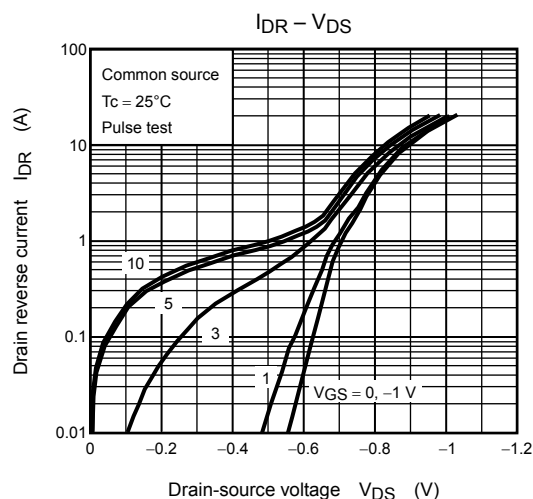
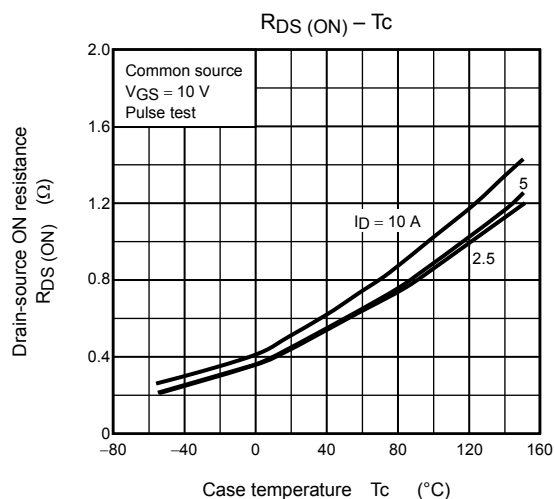
## Source-Drain Ratings and Characteristics (Ta = 25°C)

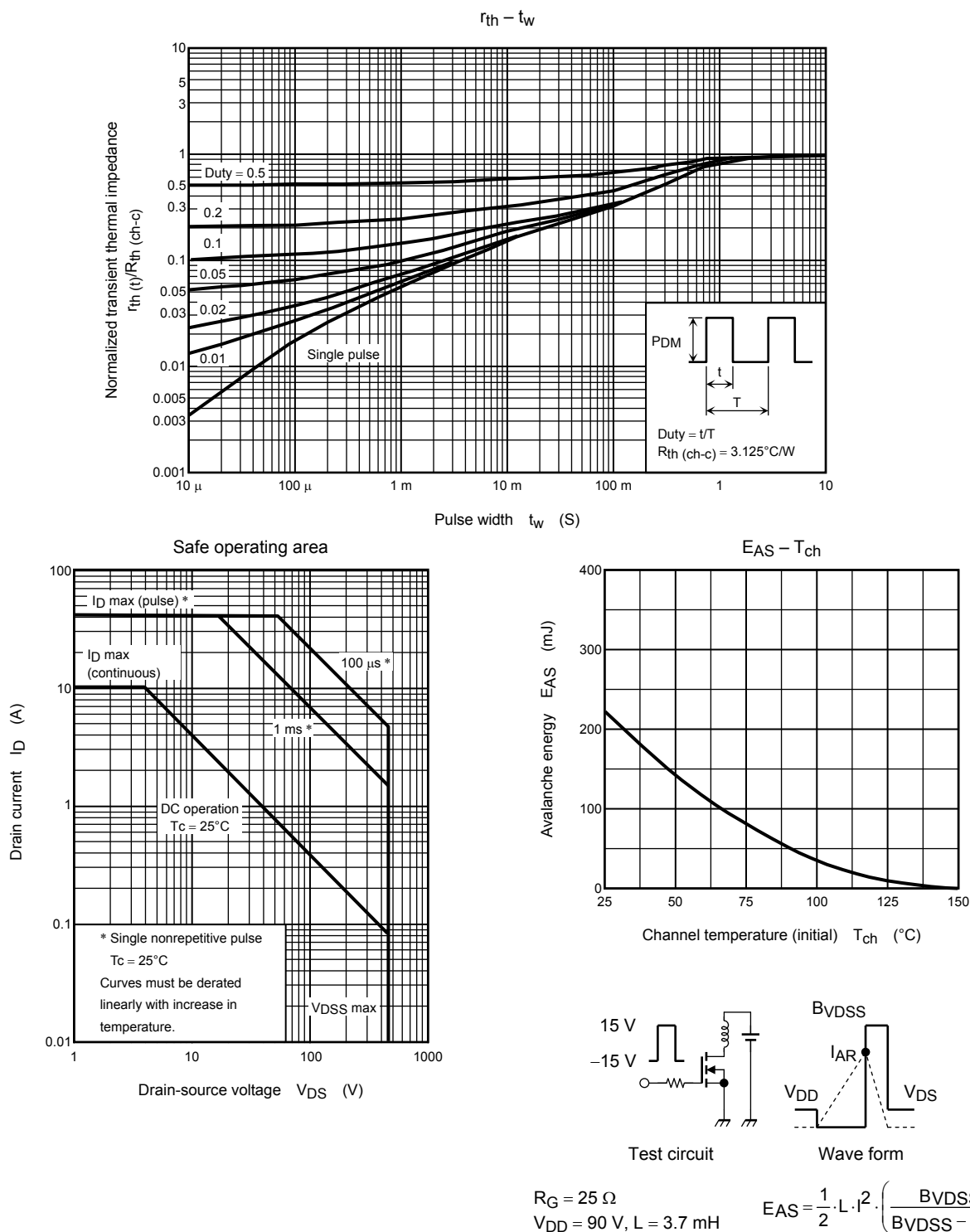
Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Continuous drain reverse current (Note 1)	$I_{DR}$	—	—	—	10	A
Pulse drain reverse current (Note 1)	$I_{DRP}$	—	—	—	40	A
Forward voltage (diode)	$V_{DSF}$	$I_{DR} = 10 \text{ A}$ , $V_{GS} = 0 \text{ V}$	—	—	−1.7	V
Reverse recovery time	$t_{rr}$	$I_{DR} = 10 \text{ A}$ , $V_{GS} = 0 \text{ V}$ ,	—	280	—	ns
Reverse recovery charge	$Q_{rr}$	$dI_{DR}/dt = 100 \text{ A}/\mu\text{s}$	—	2.7	—	$\mu\text{C}$

## Marking









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